

Features

- 3rd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q,,)
- Halogen free, RoHS compliant

Benefits

- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency

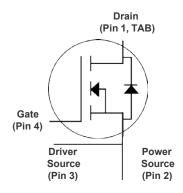
Applications

- Renewable energy
- EV battery chargers
- High voltage DC/DC converters
- Switch Mode Power Supplies









Maximum Ratings (T_c = 25 °C unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions
V_{DSmax}	Drain - Source Voltage	1200	V	$V_{GS} = 0 \text{ V}, I_{D} = 100 \mu\text{A}$
V_{GSmax}	Gate - Source Voltage (dynamic)	-10/+25	٧	AC (f >1 Hz)
V_{GSop}	Gate - Source Voltage (static)	-5/+20	V	Static
	I _D Continuous Drain Current		А	V _{GS} = 15 V, T _C = 25°C
I _D			A	V _{GS} = 15 V, T _C = 100°C
I _{D(pulse)}	Pulsed Drain Current	TBD	А	Pulse width t _P limited by T _{jmax}
P_{D}	Power Dissipation	405	W	T _c =25°C, T _J = 175 °C
T_{J} , T_{stg}	Operating Junction and Storage Temperature	-40 to +175	°C	
T _L	Solder Temperature	260	°C	1.6mm (0.063") from case for 10s

30

HSCTWA60N120G24

SiC Power MOSFET N-Channel Enhancement Mode

Electrical Characteristics (T_C = 25°C unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions	Note
V _{(BR)DSS}	Drain-Source Breakdown Voltage	1200			V	V _{GS} = 0 V, I _D = 100 μA	
V	Cata Threshold Voltage	2.0	2.5	4.0	V	$V_{DS} = V_{GS}$, $I_D = 10 \text{ mA}$	Fig. 11
$V_{GS(th)}$	Gate Threshold Voltage		1.5		V	$V = V_{DS} = V_{GS}, I_D = 10 \text{ mA}, T_J = 175^{\circ}\text{C}$] Fig. 11
I _{DSS}	Zero Gate Voltage Drain Current		1	50	μΑ	V _{DS} = 1200 V, V _{GS} = 0 V	
I _{GSS}	Gate-Source Leakage Current		10	200	nA	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	
		-200	-10		nA	$V_{GS} = -10 \text{ V}, V_{DS} = 0 \text{ V}$	
R	Drain-Source On-State Resistance		40	50	mΩ	V _{GS} = 20 V, I _D = 40 A	Fig. 4, 5, 6
R _{DS(on)}	Brain-oddree on-otate resistance		59		11122	V _{GS} = 20 V, I _D = 40 A, T _J = 175°C	
g _{fs}	Transconductance		10.4		S	V _{DS} = 20 V, I _{DS} = 40 A	Fig. 7
9ts	Transconductance		7.7			V _{DS} = 20 V, I _{DS} = 40 A, T _J = 175°C	
C_{iss}	Input Capacitance		2101			., ., ., ., ., ., ., ., ., ., ., ., ., .	Fig. 17,
Coss	Output Capacitance		161		pF	$V_{GS} = 0 \text{ V}, V_{DS} = 1000 \text{ V}$	
C _{rss}	Reverse Transfer Capacitance		14			f=100kHz V _{AC} = 25 mV	
Eoss	Coss Stored Energy		90		μJ		Fig. 16
Eon	Turn-On Switching Energy (SiC Diode FWD)		1100			V_{DS} = 800 V, V_{GS} = -5 V/+20 V, I_{D} = 40 A, $R_{G(ext)}$ = 2.5 Ω , L= 100 μ H, Tj = 175 $^{\circ}$ C	Fig. 26
E _{OFF}	Turn Off Switching Energy (SiC Diode FWD)		900		μJ		
$t_{d(on)}$	Turn-On Delay Time		22				
t _r	Rise Time		49		1	$V_{DD} = 800 \text{ V}, V_{GS} = -5 \text{ V}/20 \text{ V}$ $R_{G(ext)} = 2.5 \Omega, I_D = 40 \text{ A}$ Timing relative to V_{DS}	Fig. 27
$t_{d(off)}$	Turn-Off Delay Time		71		ns		
t _f	Fall Time		23				
R _{G(int)}	Internal Gate Resistance		1.7		Ω	f = 1 MHz, V _{AC} = 25 mV	
Q _{gs}	Gate to Source Charge		33		nC	V _{DS} = 800 V, V _{GS} = -5 V/20 V	Fig. 12
Q_{gd}	Gate to Drain Charge		51]		1	
Qg	Total Gate Charge		131	7			

Reverse Diode Characteristics (T_C = 25°C unless otherwise specified)

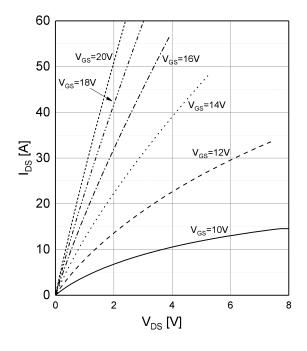
Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note
	Diode Forward Voltage	4.1		V	V _{GS} = -5 V, I _{SD} = 20 A, T _J = 25 °C	Fig. 8,
V _{SD}	Diode Porward Voltage	3.5		V	V _{GS} = -5 V, I _{SD} = 20 A, T _J = 175 °C	9, 10
Is	Continuous Diode Forward Current		83	А	V _{GS} = -4 V, T _C = 25°C	Note 1
I _{S, pulse}	Diode pulse Current		TBD	А	$V_{GS} = -4 \text{ V}$, pulse width t_P limited by T_{jmax}	Note 1
t _{rr}	Reverse Recover time	56		ns		
Q _{rr}	Reverse Recovery Charge	508		nC	$V_{GS} = -5 \text{ V}, I_{SD} = 40 \text{ A}, V_{R} = 800 \text{ V}$ $dif/dt = 2250 \text{ A}/\mu\text{s}, T_{I} = 175 \text{ °C}$	Note 1
I	Peak Reverse Recovery Current	18		А	. ,	

Thermal Characteristics

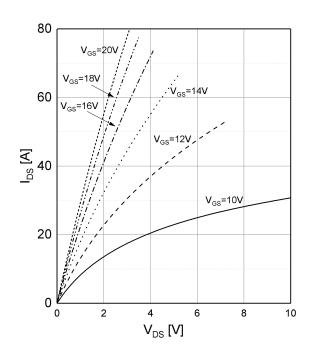
	Symbol	Parameter	Тур.	Unit	Test Conditions	Note
	R _{eJC}	Thermal Resistance from Junction to Case	0.25			Fig. 04
Г	$R_{\theta JA}$	Thermal Resistance From Junction to Ambient	40	°C/W		Fig. 21



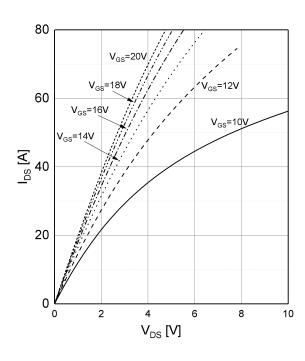
Output characteristics I_{DS} =f(V_{DS}), T_J =-55°C



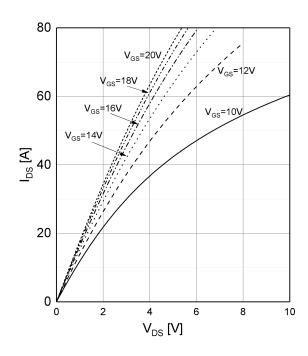
Output characteristics I_{DS} =f(V_{DS}), T_J =25°C



Output characteristics I_{DS}=f(V_{DS}), T_J=150°C

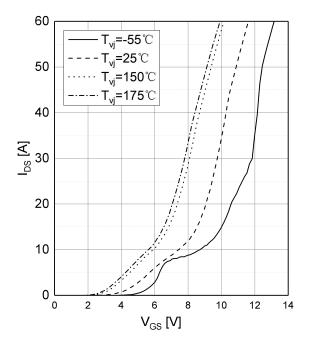


Output characteristics I_{DS}=f(V_{DS}), T_J=175°C

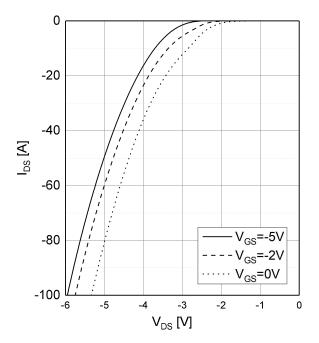




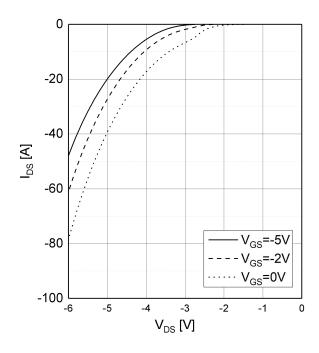
Transfer Characteristics I_{DS} =f(V_{GS}), V_{DS}=20V



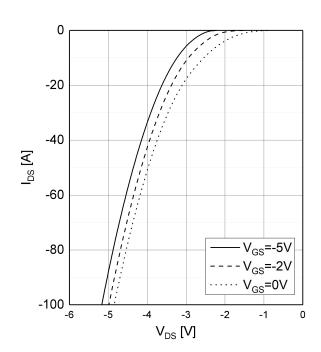
Body Diode Characteristics I_{DS} =f(V_{DS}), T_J =25°C



Body Diode Characteristics I_{DS} =f(V_{DS}), T_{J} =-55 $^{\circ}\mathrm{C}$

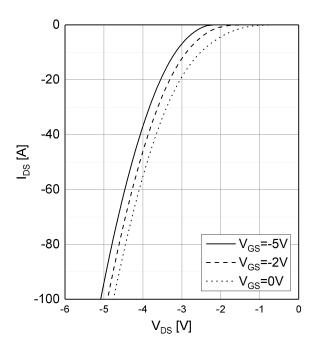


Body Diode Characteristics $I_{DS} = f(V_{DS}), T_J = 150$ °C

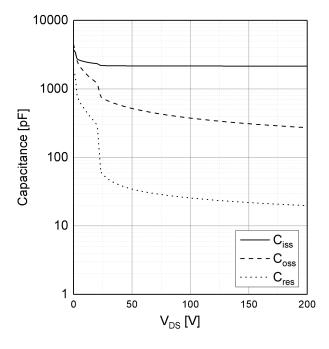




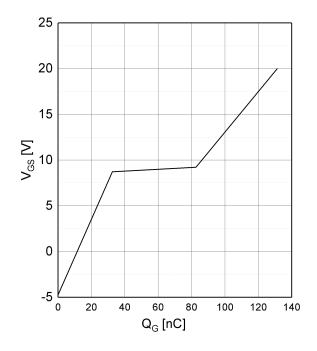
Body Diode Characteristics $I_{DS} = f(V_{DS}), T_J = 175^{\circ}C$



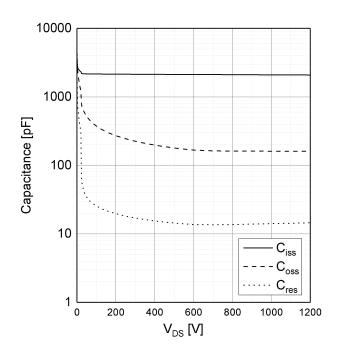
Capacitances vs Drain-Source Voltage (0-200V) $C=f(V_{DS}), T_J=25^{\circ}C, V_{AC}=25mV, f=100KHz$



Gate Charge Characteristics V_{GS} =f(Q_G), I_{DS} =40A, V_{DS} =800V, T_J =25°C

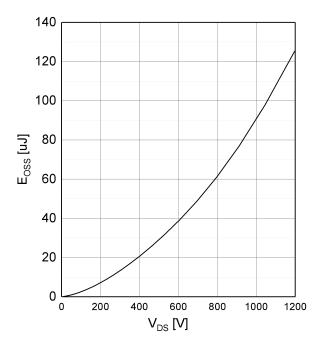


Capacitances vs Drain-Source Voltage (0-1200V) C=f(V_Ds), T_J =25°C, V_{AC} =25mV, f=100KHz

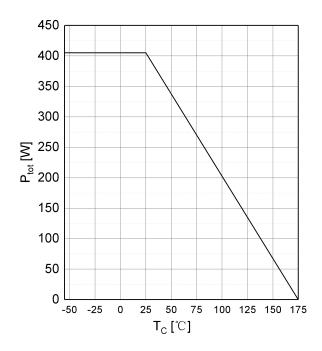




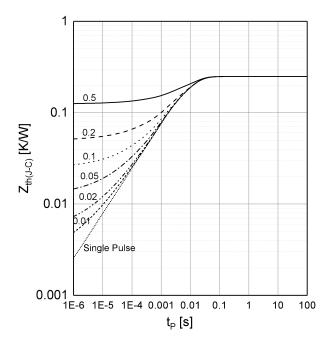
Output Capacitor Stored Energy $E_{OSS} = f(V_{DS}), T_J = 25$ °C

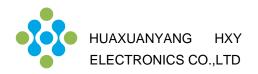


 $\label{eq:maximum} \begin{aligned} &\text{Maximum Power Dissipation Derating} \\ &P_{tot} = &f(T_{\text{C}}), \ T_{\text{J}} \!\! \leq \! 175^{\circ} \! \text{C} \end{aligned}$



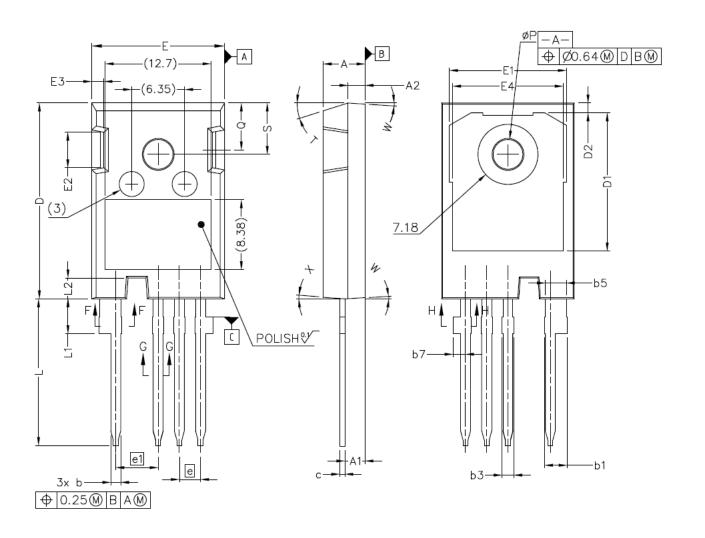
Transient Thermal Impedance (Junction to Case) $Z_{\text{th(J-C)}}\text{=}f(t),\,T_{\text{C}}\text{=}25^{\circ}\!\text{C}$

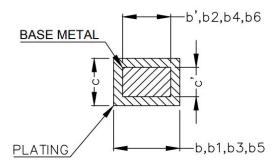




Package Dimensions

Package TO-247H-4L(TO-247H-4)





SECTION "F-F", "G-G" AND "H-H" SCALE: NONE



Package Dimensions

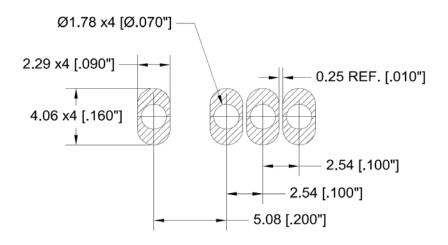
Package TO-247H-4L(TO-247H-4)

NOTE;

- 1. ALL METAL SURFACES: TIN PLATED, EXCEPT AREA OF CUT
- 2. DIMENSIONING & TOLERANCEING CONFIRM TO ASME Y14.5M-1994.
- 3. ALL DIMENSIONS ARE IN MILLIMETERS. ANGLES ARE IN DEGREES.
- 4. 'N' IS THE NUMBER OF TERMINAL POSITIONS

SYM	MILLIMETERS					
STIVI	MIN	MAX				
Α	4.83	5.21				
A1	2.29	2.54				
A2	1.91	2.16				
b`	1.07	1.28				
b	1.07	1.33				
b1	2.39	2.94				
b2	2.39	2.84				
b3	1.07	1.60				
b4	1.07	1.50				
b5	2.39	2.69				
b6	2.39	2.64				
b7	1.30	1.70				
c`	0.55	0.65				
С	0.55	0.68				
D	23.30	23.60				
D1	16.25	17.65				
D2	0.95	1.25				
Е	15.75	16.13				

SYM	MILLIMETERS				
31101	MIN	MAX			
E1	13.10	14.15			
E2	3.68	5.10			
E3	1.00	1.90			
E4	12.38	13.43			
е	2.54 BSC				
e1	5.08 BSC				
N*	4				
L	17.31	17.82			
L1	3.97	4.37			
L2	2.35	2.65			
ØΡ	3.51	3.65			
Q	5.49	6.00			
S	6.04	6.30			
Т	17.5° REF.				
W	3.5° REF.				
Χ	4° REF.				



SiC Power MOSFET N-Channel Enhancement Mode

Attention

- Any and all HUA XUAN YANG ELECTRONICS products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your HUA XUAN YANG ELECTRONICS representative nearest you before using any HUA XUAN YANG ELECTRONICS products described or contained herein in such applications.
- HUA XUAN YANG ELECTRONICS assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all HUA XUAN YANG ELECTRONICS products described or contained herein.
- Specifications of any and all HUA XUAN YANG ELECTRONICS products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- HUA XUAN YANG ELECTRONICS CO.,LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all HUA XUAN YANG ELECTRONICS products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of HUA XUAN YANG ELECTRONICS CO.,LTD.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. HUA XUAN YANG ELECTRONICS believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc.

 When designing equipment, refer to the "Delivery Specification" for the HUA XUAN YANG ELECTRONICS product that you intend to use.